

<b>PCN Number:</b>	20170109001	<b>PCN Date:</b>	Jan. 27, 2017
<b>Title:</b>	Datasheet for THS4551		
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Dept:</b>	Quality Services
<b>Proposed 1<sup>st</sup> Ship Date:</b>	Apr. 27, 2017		
<b>Change Type:</b>			
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design
<input type="checkbox"/>	Assembly Process	<input checked="" type="checkbox"/>	Data Sheet
<input type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
		<input type="checkbox"/>	Wafer Bump Site
		<input type="checkbox"/>	Wafer Bump Material
		<input type="checkbox"/>	Wafer Bump Process
		<input type="checkbox"/>	Wafer Fab Site
		<input type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>	Wafer Fab Process

### Notification Details

#### Description of Change:

The product datasheet(s) is being updated as summarized below.

The following change history provides further details.



**THS4551**

SBOS778B –APRIL 2016 –REVISED NOVEMBER 2016

#### Changes from Revision A (August 2016) to Revision B

Page

• Changed $I_{OQ}$ value in THS4551 row of <i>Device Family Comparison</i> .....	4
• Added second row and footnote 2 to <i>Voltage</i> parameter of <i>Absolute Maximum Ratings</i> table .....	5
• Added package differences and footnote 3 to <i>ESD Ratings</i> table .....	5
• Changed footnotes 1 and 2 in <i>5-V Electrical Characteristics</i> table .....	6
• Added test conditions to $A_{OL}$ parameter in <i>5-V Electrical Characteristics</i> table .....	7
• Changed <i>Input offset voltage drift</i> parameter .....	7
• Changed $I_{IB}$ parameter minimum and maximum specifications in last three rows .....	7
• Changed <i>Input bias current drift</i> parameter test conditions and specifications .....	7
• Added <i>Input offset current drift</i> parameter test conditions, minimum and maximum specifications, and test level value to second row .....	7
• Changed test conditions of <i>Common-mode input, low</i> and <i>Common-mode input, high</i> parameters .....	7
• Changed test conditions of <i>Continuous output current</i> and <i>Linear output current</i> parameters .....	8
• Changed test conditions of <i>Enable voltage threshold</i> and <i>Disable voltage threshold</i> parameters .....	8
• Changed specifications of <i>Power-down quiescent current</i> parameter .....	8
• Changed <i>Common-mode loop supply headroom to negative supply</i> parameter test conditions .....	9
• Changed test conditions and maximum specifications of <i>Common-mode loop supply headroom to positive supply</i> parameter .....	9
• Added test conditions to DC Performance, $A_{OL}$ parameter .....	10
• Changed <i>Input offset voltage drift</i> parameter test conditions in first row, added second row .....	10
• Changed minimum and maximum specifications in last three rows of $I_{IB}$ parameter .....	10

• Changed <i>Input bias current drift</i> parameter test conditions.....	10
• Added second row to <i>Input offset current drift</i> parameter .....	10
• Changed test conditions of <i>Common-mode input, low</i> and <i>Common-mode input, high</i> parameters.....	10
• Changed test conditions of <i>Continuous output current</i> and <i>Linear output current</i> parameters .....	11
• Changed test conditions of <i>Enable voltage threshold</i> and <i>Disable voltage threshold</i> parameters .....	11
• Changed $I_{Q(PD)}$ parameter specifications .....	11
• Changed <i>Common-mode loop supply headroom to negative supply</i> parameter test conditions.....	12
• Changed <i>Common-mode loop supply headroom to positive supply</i> parameter test conditions and maximum specifications .....	12
• Changed conditions of <a href="#">Figure 49</a> to <a href="#">Figure 54</a> .....	21
• Changed <i>Single-Ended Source</i> to a <i>Differential Gain of a 1-V/V Test Circuit</i> figure .....	23
• Changed main <i>Device Functional Modes</i> section: changed value of $\overline{PD}$ pin voltage .....	38
• Changed the minimum value for single-supply operation in the <i>Operating the Power Shutdown Feature</i> section .....	45
• Added SBOS476, SBOC466, SBOC463, SBOC467, SBOS460, SBOC477, SBOC472, SLOC341, SBOC469, SBOC462, SBOC461, SBOC465, SBOC464, SBOC475, SBOC474, SBOC471, SBOC459, SBOC470, SBOC468, and SBOC473 to <i>Related Documentation</i> section .....	62

The datasheet number will be changing.

Device Family	Change From:	Change To:
THS4551	SBOS778A	<b>SBOS778B</b>

These changes may be reviewed at the datasheet links provided.

<http://www.ti.com/product/THS4551>

**Reason for Change:**

To more accurately reflect device characteristics.

**Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):**

No anticipated impact. This is a specification change announcement only. There are no changes to the actual device.

**Changes to product identification resulting from this PCN:**

None.

**Product Affected:**

THS4551IDGKR	THS4551IDGKT	THS4551IRGTR	THS4551IRGTT	
THS4551IRUNR	THS4551IRUNT			

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>